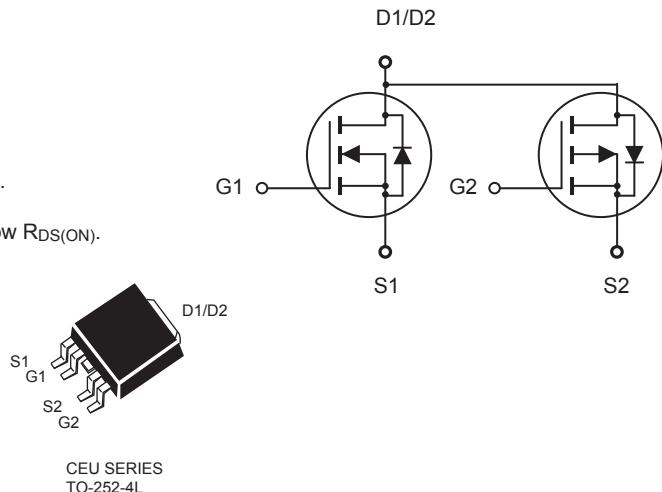


**Dual Enhancement Mode Field Effect Transistor (N and P Channel)****FEATURES**

- 40V , 14A ,  $R_{DS(ON)} = 32m\Omega$  @ $V_{GS} = 10V$ .  
 $R_{DS(ON)} = 46m\Omega$  @ $V_{GS} = 4.5V$ .
- -40V , -12A ,  $R_{DS(ON)} = 45m\Omega$  @ $V_{GS} = 10V$ .  
 $R_{DS(ON)} = 65m\Omega$  @ $V_{GS} = 4.5V$ .
- Super high dense cell design for extremely low  $R_{DS(ON)}$ .
- High power and current handing capability.
- Lead free product is acquired.
- TO-252-4L package.

**ABSOLUTE MAXIMUM RATINGS**  $T_C = 25^\circ C$  unless otherwise noted

Parameter	Symbol	N-Channel	P-Channel	Units
Drain-Source Voltage	$V_{DS}$	40	40	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	$\pm 20$	V
Drain Current-Continuous <sup>e</sup>	$I_D$ <sup>e</sup>	14	-12	A
Drain Current-Pulsed <sup>a</sup>	$I_{DM}$	56	-48	A
Maximum Power Dissipation @ $T_C = 25^\circ C$ - Derate above $25^\circ C$	$P_D$	10.4 0.08		W W/ $^\circ C$
Operating and Store Temperature Range	$T_J, T_{Stg}$	-55 to 150		$^\circ C$

**Thermal Characteristics**

Parameter	Symbol	Limit	Units
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	12	$^\circ C/W$
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	50	$^\circ C/W$



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**N-Channel Electrical Characteristics**  $T_A = 25^\circ\text{C}$  unless otherwise noted

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
<b>Off Characteristics</b>						
Drain-Source Breakdown Voltage	$\text{BV}_{\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	40			V
Zero Gate Voltage Drain Current	$I_{\text{DSS}}$	$V_{\text{DS}} = 40\text{V}, V_{\text{GS}} = 0\text{V}$			1	$\mu\text{A}$
Gate Body Leakage Current, Forward	$I_{\text{GSSF}}$	$V_{\text{GS}} = 20\text{V}, V_{\text{DS}} = 0\text{V}$			100	nA
Gate Body Leakage Current, Reverse	$I_{\text{GSSR}}$	$V_{\text{GS}} = -20\text{V}, V_{\text{DS}} = 0\text{V}$			-100	nA
<b>On Characteristics</b>						
Gate Threshold Voltage	$V_{\text{GS(th)}}$	$V_{\text{GS}} = V_{\text{DS}}, I_D = 250\mu\text{A}$	1		3	V
Static Drain-Source On-Resistance	$R_{\text{DS(on)}}$	$V_{\text{GS}} = 10\text{V}, I_D = 7\text{A}$		25	32	$\text{m}\Omega$
		$V_{\text{GS}} = 4.5\text{V}, I_D = 5\text{A}$		35	46	$\text{m}\Omega$
<b>Dynamic Characteristics<sup>d</sup></b>						
Forward Transconductance	$g_{\text{FS}}^{\text{c}}$	$V_{\text{DS}} = 10\text{V}, I_D = 7\text{A}$		3		S
Input Capacitance	$C_{\text{iss}}$	$V_{\text{DS}} = 20\text{V}, V_{\text{GS}} = 0\text{V}, f = 1.0 \text{ MHz}$		1050		pF
Output Capacitance	$C_{\text{oss}}$			155		pF
Reverse Transfer Capacitance	$C_{\text{rss}}$			95		pF
<b>Switching Characteristics<sup>d</sup></b>						
Turn-On Delay Time	$t_{\text{d(on)}}$	$V_{\text{DD}} = 20\text{V}, I_D = 6\text{A}, V_{\text{GS}} = 10\text{V}, R_{\text{GEN}} = 3\Omega$		14	30	ns
Turn-On Rise Time	$t_r$			10	20	ns
Turn-Off Delay Time	$t_{\text{d(off)}}$			17	35	ns
Turn-Off Fall Time	$t_f$			18	35	ns
Total Gate Charge	$Q_g$	$V_{\text{DS}} = 20\text{V}, I_D = 6\text{A}, V_{\text{GS}} = 10\text{V}$		20.5	27	nC
Gate-Source Charge	$Q_{\text{gs}}$			3.5		nC
Gate-Drain Charge	$Q_{\text{gd}}$			4.0		nC
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
Drain-Source Diode Forward Current <sup>b</sup>	$I_S$				8	A
Drain-Source Diode Forward Voltage <sup>c</sup>	$V_{\text{SD}}$	$V_{\text{GS}} = 0\text{V}, I_S = 1.0\text{A}$			1.2	V
<b>Notes :</b>						
a.Repetitive Rating : Pulse width limited by maximum junction temperature. <sup>d</sup>						
b.Surface Mounted on FR4 Board, $t \leq 10 \text{ sec.}$ <sup>d</sup>						
c.Pulse Test : Pulse Width $\leq 300\mu\text{s}$ , Duty Cycle $\leq 2\%$ . <sup>d</sup>						
d.Guaranteed by design, not subject to production testing. <sup>d</sup>						
e.Calculated continuous current based on the maximum allowable junction temperature. Package limitation current=8A.						



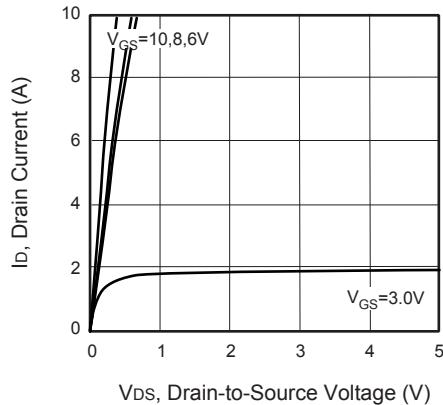
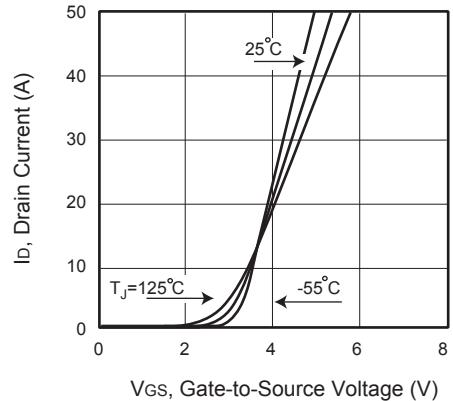
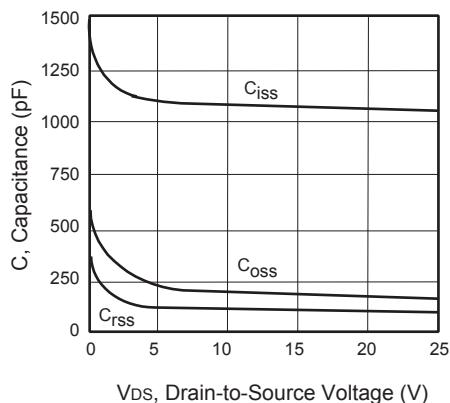
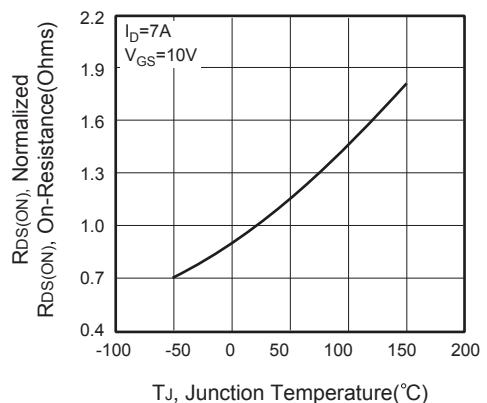
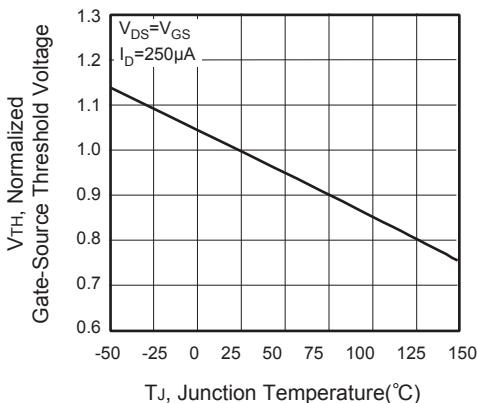
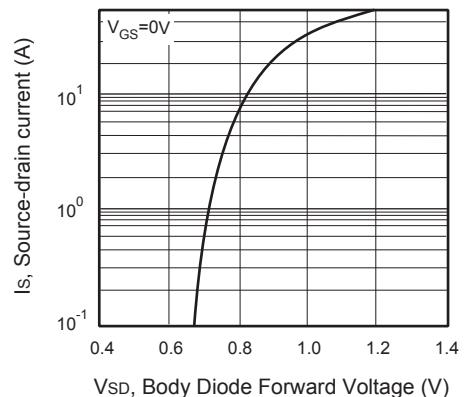
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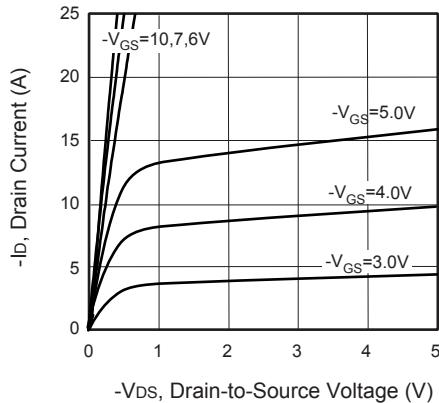
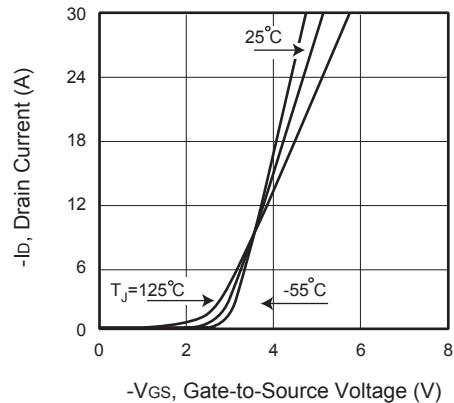
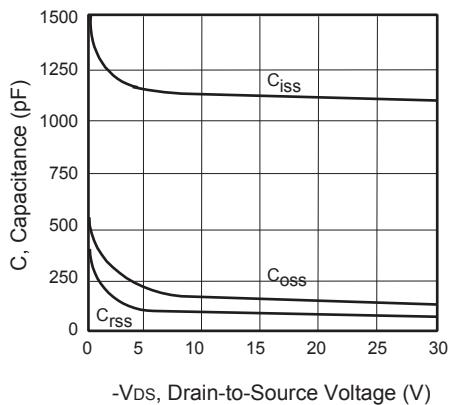
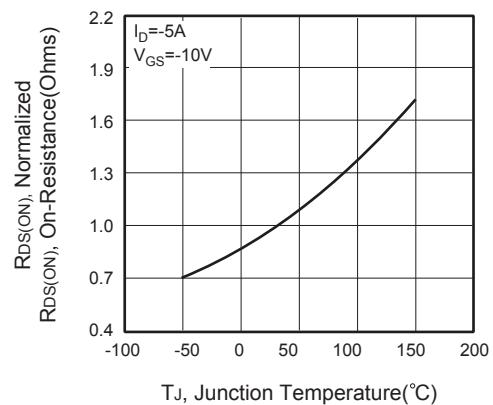
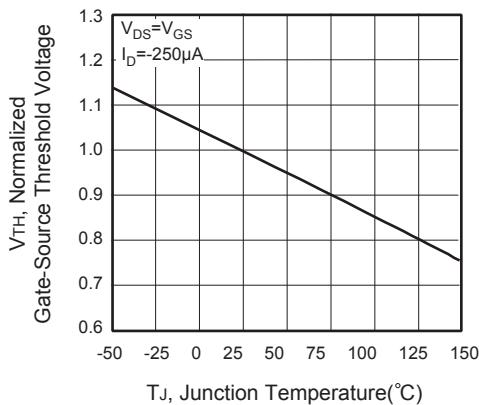
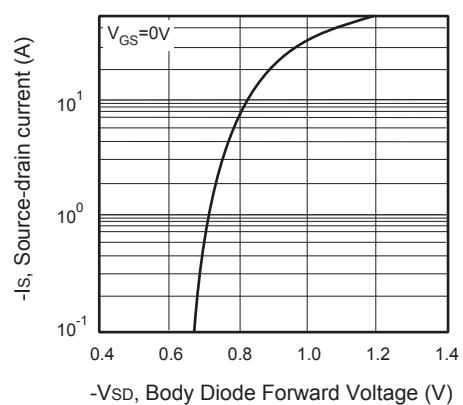
## P-Channel Electrical Characteristics $T_A = 25^\circ\text{C}$ unless otherwise noted

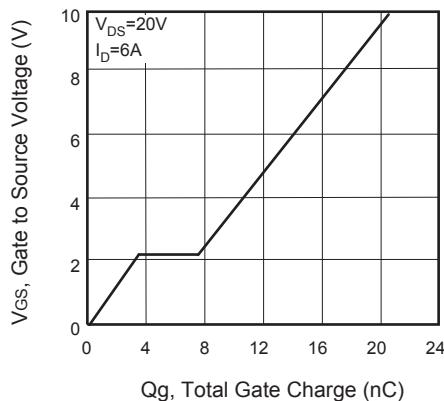
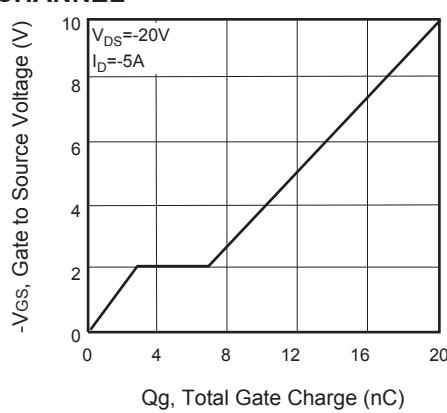
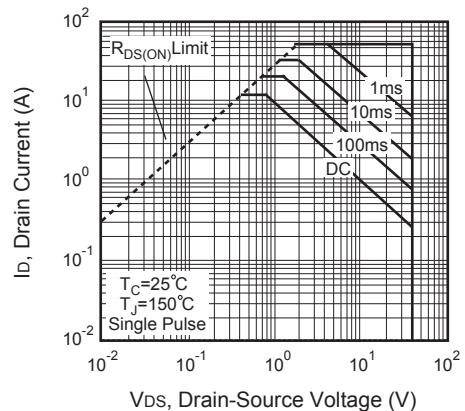
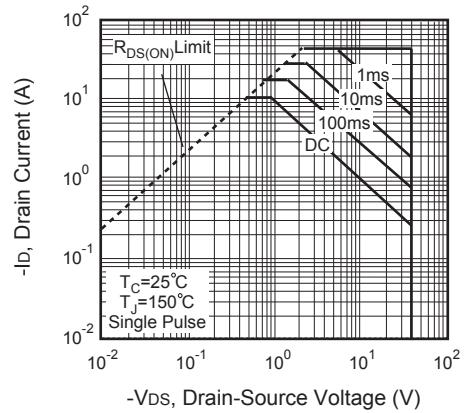
Parameter	Symbol	Test Condition	Min	Typ	Max	Units
<b>Off Characteristics</b>						
Drain-Source Breakdown Voltage	$\text{BV}_{\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_{\text{D}} = -250\mu\text{A}$	-40			V
Zero Gate Voltage Drain Current	$I_{\text{DSS}}$	$V_{\text{DS}} = -40\text{V}, V_{\text{GS}} = 0\text{V}$			-1	$\mu\text{A}$
Gate Body Leakage Current, Forward	$I_{\text{GSSF}}$	$V_{\text{GS}} = 20\text{V}, V_{\text{DS}} = 0\text{V}$			100	nA
Gate Body Leakage Current, Reverse	$I_{\text{GSSR}}$	$V_{\text{GS}} = -20\text{V}, V_{\text{DS}} = 0\text{V}$			-100	nA
<b>On Characteristics</b>						
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{GS}} = V_{\text{DS}}, I_{\text{D}} = -250\mu\text{A}$	-1		-3	V
Static Drain-Source On-Resistance	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}} = -10\text{V}, I_{\text{D}} = -5\text{A}$		37	45	$\text{m}\Omega$
		$V_{\text{GS}} = -4.5\text{V}, I_{\text{D}} = -3\text{A}$		50	65	$\text{m}\Omega$
<b>Dynamic Characteristics<sup>d</sup></b>						
Forward Transconductance <sup>c</sup>	$g_{\text{FS}}$	$V_{\text{DS}} = -10\text{V}, I_{\text{D}} = -5\text{A}$		3		S
Input Capacitance	$C_{\text{iss}}$	$V_{\text{DS}} = -20\text{V}, V_{\text{GS}} = 0\text{V}, f = 1.0 \text{ MHz}$		1125		pF
Output Capacitance	$C_{\text{oss}}$			150		pF
Reverse Transfer Capacitance	$C_{\text{rss}}$			100		pF
<b>Switching Characteristics<sup>d</sup></b>						
Turn-On Delay Time	$t_{\text{d}(\text{on})}$	$V_{\text{DD}} = -20\text{V}, I_{\text{D}} = -5\text{A}, V_{\text{GS}} = -10\text{V}, R_{\text{GEN}} = 3\Omega$		12	24	ns
Turn-On Rise Time	$t_r$			5	10	ns
Turn-Off Delay Time	$t_{\text{d}(\text{off})}$			33	66	ns
Turn-On Fall Time	$t_f$			4	8	ns
Total Gate Charge	$Q_g$	$V_{\text{DS}} = -20\text{V}, I_{\text{D}} = -5\text{A}, V_{\text{GS}} = -10\text{V}$		20	26	nC
Gate-Source Charge	$Q_{\text{gs}}$			3		nC
Gate-Drain Charge	$Q_{\text{gd}}$			4		nC
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
Drain-Source Diode Forward Current <sup>b</sup>	$I_s$				-8	A
Drain-Source Diode Forward Voltage <sup>c</sup>	$V_{\text{SD}}$	$V_{\text{GS}} = 0\text{V}, I_s = -1.0\text{A}$			-1.2	V

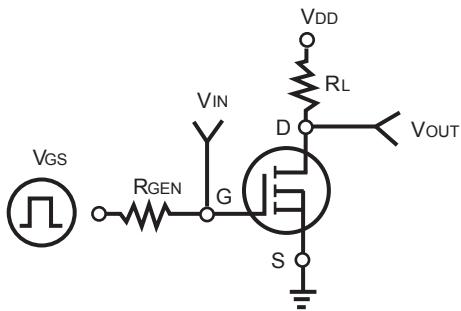
Notes :

- a.Repetitive Rating : Pulse width limited by maximum junction temperature.<sup>e</sup>
- b.Surface Mounted on FR4 Board, t ≤ 10 sec.<sup>e</sup>
- c.Pulse Test : Pulse Width ≤ 300μs, Duty Cycle ≤ 2%.<sup>e</sup>
- d.Guaranteed by design, not subject to production testing.<sup>e</sup>
- e.Calculated continuous current based on the maximum allowable junction temperature. Package limitation current=8A.

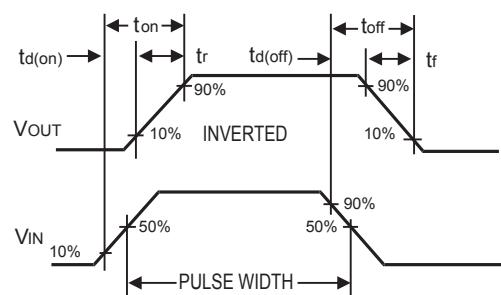
**N-CHANNEL**

**Figure 1. Output Characteristics**

**Figure 2. Transfer Characteristics**

**Figure 3. Capacitance**

**Figure 4. On-Resistance Variation with Temperature**

**Figure 5. Gate Threshold Variation with Temperature**

**Figure 6. Body Diode Forward Voltage Variation with Source Current**

**P-CHANNEL**

**Figure 7. Output Characteristics**

**Figure 8. Transfer Characteristics**

**Figure 9. Capacitance**

**Figure 10. On-Resistance Variation with Temperature**

**Figure 11. Gate Threshold Variation with Temperature**

**Figure 12. Body Diode Forward Voltage Variation with Source Current**

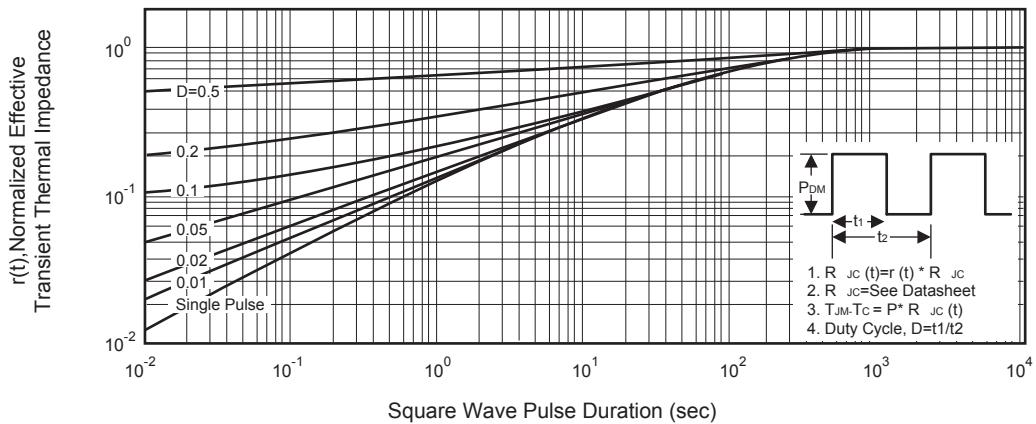
**N-CHANNEL**

**Figure 13. Gate Charge**
**P-CHANNEL**

**Figure 15. Gate Charge**

**Figure 14. Maximum Safe Operating Area**

**Figure 16. Maximum Safe Operating Area**



**Figure 17. Switching Test Circuit**



**Figure 18. Switching Waveforms**



**Figure 19. Normalized Thermal Transient Impedance Curve**